The conference is part of the iCT conference series, which represent a key appointment for networking and knowledge exchange in the field of industrial Computed Tomography. A growing number of researchers and industry professionals are joining this event year after year. The conference programme includes keynote speeches, oral presentations, poster sessions and industrial exhibitions.

Please, find here below the details on: submission information, important dates and accepted topics.

**SUBMISSION INFORMATION**

The submitted abstracts have been reviewed by the Scientific Committee and the accepted contributions have been selected for one of the following:
- Talk + full paper
- Poster + Short talk + full paper
- Poster + full paper
- Last minute Poster

Instructions for authors are available [here](https://www.ict2019.org/papers).

The abstracts of all accepted contributions are published in the book of abstracts and distributed at the conference. The iCT2019 full papers are published in the eJournal of Nondestructive Testing, ISSN: 1435-4934, and available as on-line proceedings on [www.ndt.net/iCT2019](https://www.ndt.net/iCT2019).

Conference language: English.

**IMPORTANT DATES**

- 1 July 2018: Abstract submission
- September 2018: Acceptance Notification
- 10 December 2018: Submission of amended abstract and full manuscript
- 10 December 2018: Submission of abstract for Last minute Poster
- 13-15 February 2019: Conference

**TOPICS**

- Computed tomography (CT) for dimensional metrology
- CT for advanced and additive manufacturing
- CT for non-destructive testing of metals, plastics, composites, ceramics and other materials
- CT for 3D material characterisation
- CT as a tool for the development of new materials and components
- CT and Industry 4.0
- Initial sampling inspection and reverse engineering
- Application of CT in automotive, aerospace and material industry
- Evaluation and visualisation of CT data
- New algorithms and software tools for processing CT data
- Correction and filter methods for the improvement of CT results
- Quantitative evaluations for CT data
- Standardisation of CT
- New CT methods for high resolution, energy dispersive and fast CT
- Synchrotron-CT methods
- New developments in CT instrument technology including X-ray detectors and sources
- Phase contrast and grating interferometer CT